# MSKSEMI 美森科







TVS



TSS



MOV



GDT



PIFF

# 2V7002LT1G-MS

**Product specification** 





#### **Features**

- 60V,0.3A, RDS(ON) =2.2Ω@VGS=10V
- Improved dv/dt capability
- Fast switching
- Green Device Available
- G-S ESD Protection Diode Embedded
- ESD protected up to 2KV

BVDSS	RDSON	ID
60V	2.2Ω	0.3A

#### **Reference News**

PACKAGE OUTLINE	Pin Configuration	Marking
SOT-23	G	.702°

# **Absolute Maximum Ratings** (TA=25 ℃ unless otherwise noted)

Symbol	Parameter	Rating	Units
Vos	Drain- Source Voltage	60	V
Vgs	Gate- Source Voltage	±20	V
I <sub>D</sub>	Drain Current – Continuous (Tc=25℃)	0.3	Α
טי	Drain Current – Continuous (T <sub>C</sub> =100℃)	0.1	А
Ідм	Drain Current – Pulsed <sup>1</sup>	0.8	А
P <sub>D</sub>	Power Dissipation (T <sub>C</sub> =25 ℃)	0.35	W
1.0	Power Dissipation – Derate above 25 ℃	0.003	W/°C
Тѕтс	Storage Temperature Range	-50 to 150	°C
TJ	Operating Junction Temperature Range	-50 to 150	°C



#### **Thermal Characteristics**

Symbol	Parameter	Тур.	Max.	Unit
Reja	Thermal Resistance Junction to ambient		357	°C/W

## **Electrical Characteristics**(TJ=25 °C , unless otherwise noted)

#### **Off Characteristics**

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
BVDSS	Drain- Source Breakdown Voltage	V <sub>GS</sub> =0V , I <sub>D</sub> =250uA	60			V
1	Drain- Source Leakage Current	V <sub>DS</sub> =60V , V <sub>GS</sub> =0V , T <sub>J</sub> =25℃			1	ŭΑ
IDSS	1	V <sub>DS</sub> =48V , V <sub>GS</sub> =0V , T <sub>J</sub> =125℃			10	uА
Igss	Gate- Source Leakage Current	V <sub>GS</sub> ±20V , V <sub>DS</sub> =0V			±10	uА

#### On Characteristics

	Static Drain-Source On-Resistance	V <sub>GS</sub> =10V , I <sub>D</sub> =0.3A		2.2	2.8	Ω
RDS(ON)	Static Drain-Source On-Nesistance	V <sub>GS</sub> =4.5V , I <sub>D</sub> =0.2A		2 4	3 0	Ω
V <sub>GS(th)</sub>	Gate Threshold Voltage	$V_{GS}=V_{DS}$ , $I_D=250uA$	1	1.6	2.5	V
gfs	Forward Transconductance	V <sub>DS</sub> =10V , I <sub>D</sub> =0.3A		0.5		S

### **Dynamic and switching Characteristics**

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Qg	Total Gate Charge <sup>2, 3</sup>		 3.7	5.6	
Qgs	Gate-Source Charge <sup>2, 3</sup>	$V_{DS}$ =30V , $V_{GS}$ =10V , $I_{D}$ =1A	 0.9	1.4	nC
Qgd	Gate-Drain Charge <sup>2, 3</sup>		 0.4	0.6	
T <sub>d(on)</sub>	Turn-On Delay Time <sup>2</sup> , <sup>3</sup>		 3	6	
Tr	Rise Time <sup>2, 3</sup>	$V_{DD}$ =30V , $V_{GS}$ =10V , $R_{G}$ =6 $\Omega$	 5	10	
T <sub>d(off)</sub>	Turn-Off Delay Time <sup>2, 3</sup>	I <sub>D</sub> =0.2A	 14	27	ns
Tf	Fall Time <sup>2 , 3</sup>		 9	17	
Ciss	Input Capacitance		 25.5	38	
Coss	Output Capacitance	V <sub>DS</sub> =30V , V <sub>GS</sub> =0V , F=1MHz	 17	26	pF
Crss	Reverse Transfer Capacitance		 7.8	12	•

### **Drain-Source Diode Characteristics and Maximum Ratings**

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
Is	Continuous Source Current	V <sub>G</sub> =V <sub>D</sub> =0V , Force Current			0.3	Α
lsм	Pulsed Source Current	VG-VD-UV, Force Current			1.2	Α
Vsp	Diode Forward Voltage	V <sub>GS</sub> =0V , I <sub>S</sub> =1A , T <sub>J</sub> =25℃			1.2	V
trr	Reverse Recovery Time	V <sub>GS</sub> =50V, I <sub>S</sub> =1A , dI/dt=100A/μs		3.4		ns
Qrr	Reverse Recovery Charge	T <sub>J</sub> =25℃		0.7		nC

#### Note:

- 1.Repetitive Rating: Pulsed width limited by maximum junction temperature.
- $2\,.$  The data tested by pulsed , pulse width  $\leqq 300\,us$  , duty cycle  $\leqq 2\,\%\,.$
- 3. Essentially independent of operating temperature.

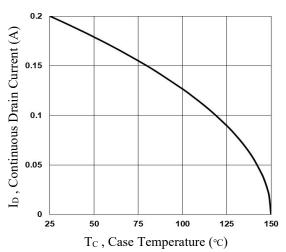


Fig.1 Continuous Drain Current vs. Tc

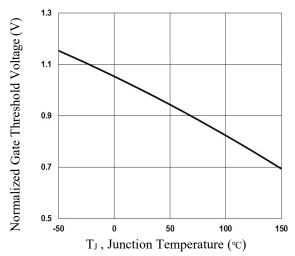


Fig.3 Normalized  $V_{th}$  vs.  $T_J$ 

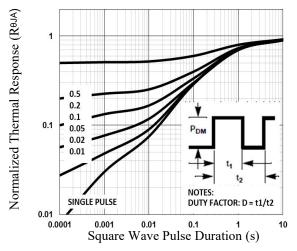


Fig.5 Normalized Transient Impedance

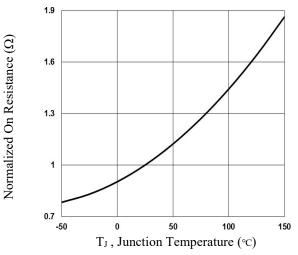


Fig.2 Normalized RDSON vs. T<sub>J</sub>

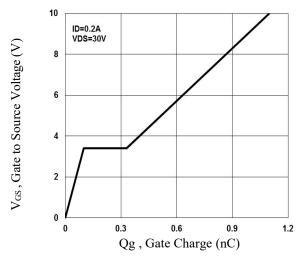


Fig.4 Gate Charge Waveform

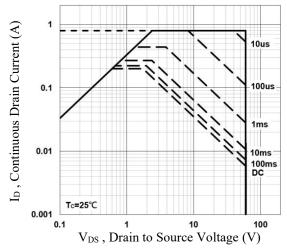
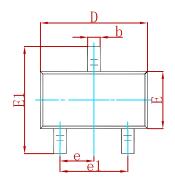
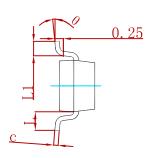


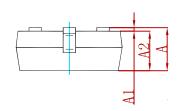
Fig.6 Maximum Safe Operation Area



## PACKAGE MECHANICAL DATA

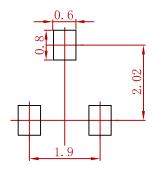






Cumbal	Dimensions	Dimensions In Millimeters		ns In Inches	
Symbol	Min	Max	Min	Max	
Α	0.900	1.150	0.035	0.045	
A1	0.000	0.100	0.000	0.004	
A2	0.900	1.050	0.035	0.041	
b	0.300	0.500	0.012	0.020	
С	0.080	0.150	0.003	0.006	
D	2.800	3.000	0.110	0.118	
E	1.200	1.400	0.047	0.055	
E1	2.250	2.550	0.089	0.100	
е	0.950 TYP		0.037	7 TYP	
e1	1.800	2.000	0.071	0.079	
L	0.550	0.550 REF 0.02		2 REF	
L1	0.300	0.500	0.012	0.020	
θ	0°	8°	0°	8°	

# **Suggested Pad Layout**



#### Note:

- 1.Controlling dimension:in millimeters.
- 2.General tolerance:± 0.05mm.
- 3. The pad layout is for reference purposes only.

## **REEL SPECIFICATION**

P/N	PKG	QTY
2V7002LT1G-MS	SOT-23	3000



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